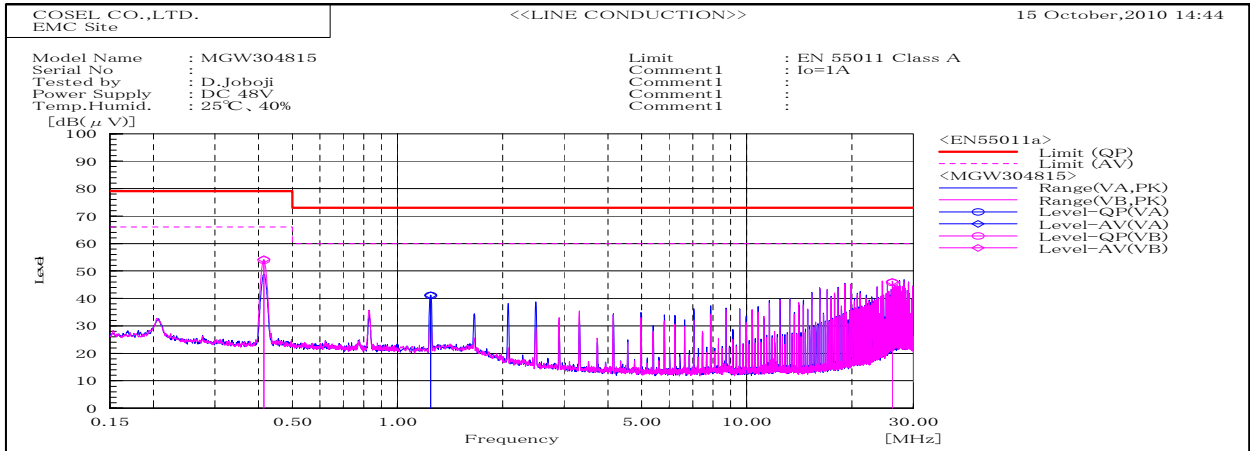
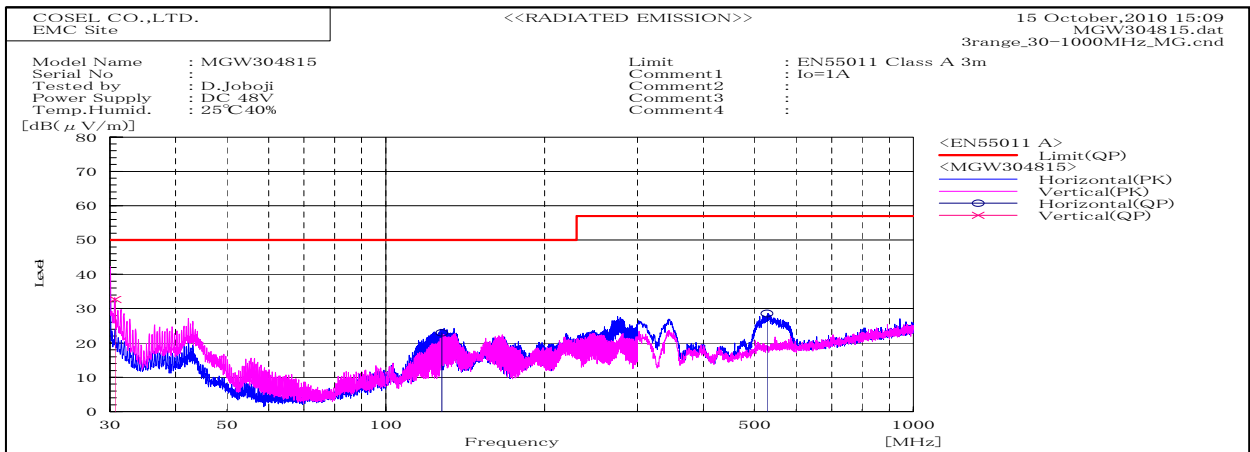


DATA SHEET		Date	19-Oct-10
Model	MGW304815	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Joboji



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.41407		VB	43.9	44.2	10	53.9	54.2	79	66	25.1	11.8	Pass	
1.24394		VA	31	31.1	10.1	41.1	41.2	73	60	31.9	18.8	Pass	
26.10895		VB	34.9	35.1	11	45.9	46.1	73	60	27.1	13.9	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP	QP				
30.673	V	Stable	46.5	-13.8		32.7		50	17.3	Pass	101	305
127.687	H	Stable	42.5	-19.6		22.9		50	27.1	Pass	157	93
527.759	H	Stable	40	-11.4		28.6		57	28.4	Pass	150	41

DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission

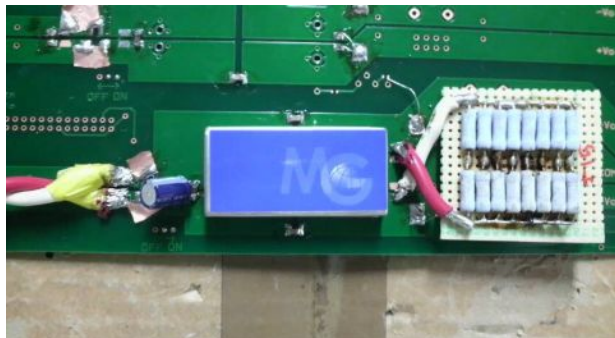


Conditions

Test : EMI
Model Name : MGS3048□□/MGW3048□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

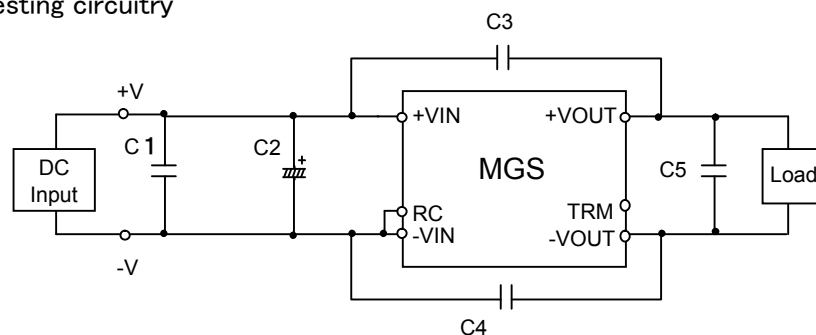


Fig.1 Testing circuitry 1

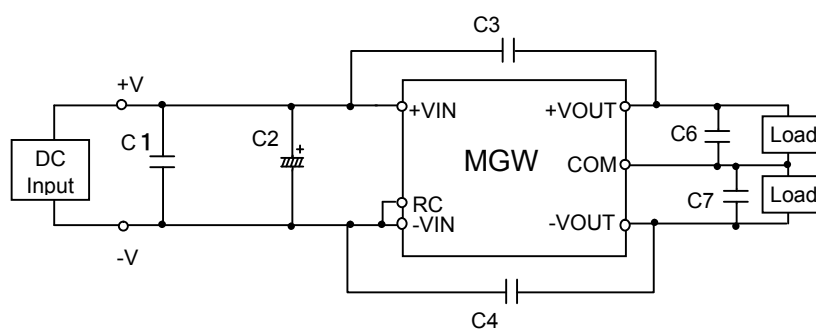


Fig.2 Testing circuitry 2

C1	:	100V	2.2 μ F	Ceramic Capacitor
C2	:	80V	47 μ F	Electrolytic Capacitor
C3,C4	:	2kV	1000pF	Ceramic Capacitor
C5,C6,C7	:	25V	22 μ F	Ceramic Capacitor